

UV absorption spectroscopy to study the role of CF radicals during cryogenic etching of Si in CF₄ plasmas

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Ultraviolet absorption spectroscopy is used to monitor the CF and CF₂ radical densities in CF₄ inductively coupled Si etching plasmas (ICP) as a function of the substrate temperature [1]. Typical spectra are shown in Fig.1. It can be seen from the absorption spectrum of the CF radical in Fig.1(a) that its density decreases dramatically when the wafer temperature is reduced from 20 to -130 °C under identical plasma conditions, demonstrating that the CF surface sticking coefficient increases as the surface temperature is reduced, while the CF₂ density remains nearly unchanged as it can be deduced from the corresponding absorption spectrum. This suggests that a CF₄ plasma could be used to form sidewall passivation layers and perform anisotropic etching at cryogenic temperature, which is impossible at room temperature.

Subsequently, a cyclical Bosch type etching process of silicon was evaluated at -100 °C using CF₄ plasma to passivate the trench sidewalls. Anisotropic etch profiles were obtained with an etch rate of 4.4 μm/min. Compared to a typical Bosch process using highly polymerizing c-C₄F₈ plasma, chamber wall contamination could be significantly reduced, alleviating a major issue of this cyclic process. Furthermore, CF₄ has a 28% lower global warming potential than c-C₄F₈.

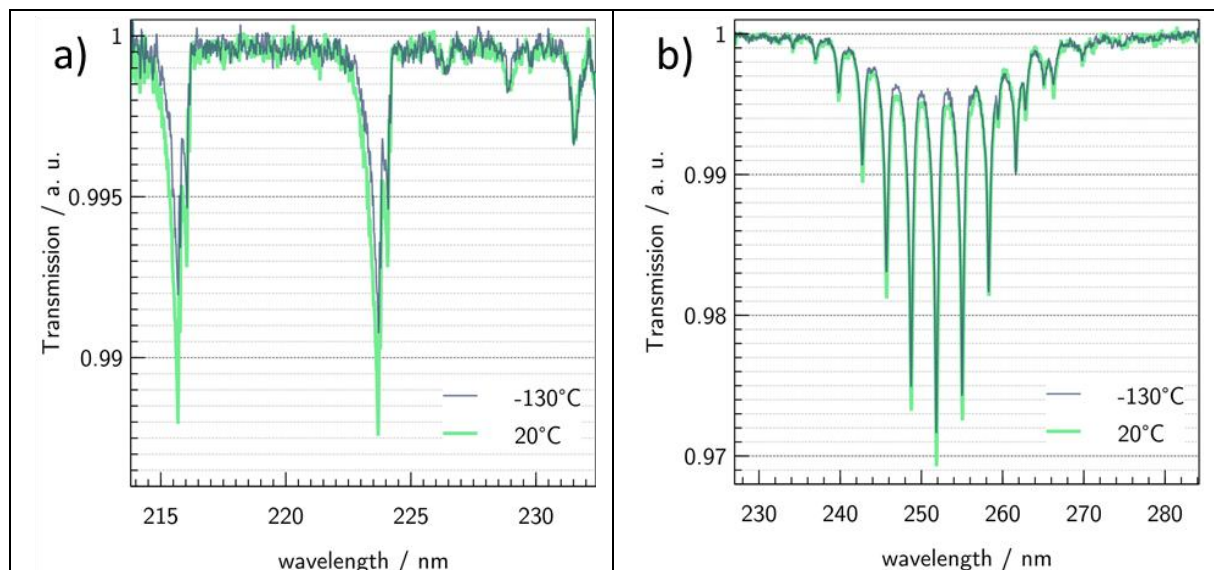


Figure 1 : Absorption spectra measured in a CF₄ plasma (50 sccm, 4 Pa, 1.5 kW ICP power, no bias power) for chuck temperatures of 20 °C and -130 °C. (a) $A\ 2\Sigma \leftarrow X\ 2\Pi\ (1,0)$ transition of CF and (b) $A(0, v, 0) \leftarrow X(0, 0, 0)$ transition of CF₂.

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Références

[1] J. Nos, S. Iséni, M. Kogelschatz, G. Cunge, P. Lefauchaux, R. Dussart, T. Tillocher, E. Despiiau-Pujo, *APL* **126**, 031602 (2025)

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